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Huo Yan Chen, T. H. Tse, F. T. Chan, T. Y. Chen

July 1998 ACM Transactions on Software Engineering and Methodology (TOSEM), Volume 7 Issue 3

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Because of the growing importance of object-oriented programming, a number of testing strategies have been proposed. They are based either on pure black-box or white-box techniques. We propose in this article a methodology to integrate the black- and white-box techniques. The black-box technique is used to select test cases. The white-box technique is mainly applied to determine whether two objects resulting from the program execution of a test care are observationally equivalent. It is als ...

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Types and persistence in database programming languages Malcolm P. Atkinson, O. Peter Buneman

June 1987 ACM Computing Surveys (CSUR), Volume 19 Issue 2

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Traditionally, the interface between a programming language and a database has either been through a set of relatively low-level subroutine calls, or it has required some form of embedding of one language in another. Recently, the necessity of integrating database and programming language techniques has received some long-overdue recognition. In response, a number of attempts have been made to construct programming languages with

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